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APPLICATION NO.	FILI	NG DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/052,989	11/09/2001		Han-Kun Hsieh	YUSO-131 1309	
7:	590	04/11/2003			
Raymond Sun 12420 Woodha				EXAMINER	
Tustin, CA 92782				VU, DAVID	
	*			ART UNIT	PAPER NUMBER
				2818	
				DATE MAILED: 04/11/2003	

Please find below and/or attached an Office communication concerning this application or proceeding.

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		Application No.	Applicant(s)
	Office Action Summan	10/052,989	HSIEH ET AL.
	Office Action Summary	Examiner	Art Unit
	7	DAVID VU	2818
Period fo	The MAILING DATE of this communication app or Reply	ears on the cover sheet with	the correspondence address
- Exte after - If the - If NC - Failu - Any r	ORTENED STATUTORY PERIOD FOR REPL'MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1.1: SIX (6) MONTHS from the mailing date of this communication. period for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period v re to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing and patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a rep within the statutory minimum of thirty will apply and will expire SIX (6) MONTH cause the application to become APA	ly be timely filed (30) days will be considered timely. 45 from the mailing date of this communication.
1)🖂	Responsive to communication(s) filed on 09 N	lovember 2001 .	
2a)	This action is FINAL. 2b)⊠ Thi	s action is non-final.	
3)☐ Dispositi	Since this application is in condition for allowa closed in accordance with the practice under a on of Claims	nce except for formal matte	ers, prosecution as to the merits is 11, 453 O.G. 213.
4) 🖾	Claim(s) 1-23 is/are pending in the application		
	4a) Of the above claim(s) is/are withdraw	n from consideration.	
	Claim(s) is/are allowed.		
6)⊠	Claim(s) 1-23 is/are rejected.		
7) 🗌	Claim(s) is/are objected to.		
8) 🗌	Claim(s) are subject to restriction and/or	election requirement.	
Application	on Papers	•	
9) 🔲 1	The specification is objected to by the Examiner		
10)⊠ Т	he drawing(s) filed on <u>09 November 2001</u> is/ard	e: a)⊠ accepted or b)⊡ obje	cted to by the Examiner.
	Applicant may not request that any objection to the	drawing(s) be held in abeyand	e. See 37 CFR 1.85(a).
11) 🗌 T	he proposed drawing correction filed on	is: a)∏ approved b)∏ disa	approved by the Examiner.
	If approved, corrected drawings are required in repl		
12) 🗌 T	he oath or declaration is objected to by the Exa	miner.	
Priority u	nder 35 U.S.C. §§ 119 and 120		
13)🛛 🛚	Acknowledgment is made of a claim for foreign	priority under 35 U.S.C. § 1	19(a)-(d) or (f).
	〗All b)□ Some * c)□ None of:		
•	1.⊠ Certified copies of the priority documents	have been received.	
	2. Certified copies of the priority documents		lication No.
	B. Copies of the certified copies of the priorit application from the International Bure se the attached detailed Office action for a list o	y documents have been rec	ceived in this National Stage
	knowledgment is made of a claim for domestic		
a)	☐ The translation of the foreign language proveknowledgment is made of a claim for domestic	sional application has been	received.
Attachment(:			
2) 🔲 Notice	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-948) tion Disclosure Statement(s) (PTO-1449) Paper No(s)	5) Notice of Infor	mary (PTO-413) Paper No(s) mal Patent Application (PTO-152)
Patent and Trad O-326 (Rev.		on Summary	Part of Paper No. 3

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DETAILED ACTION

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

1. Claims 1-3, 5-8 and 10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lu et al., (US 6,358,836) in view of Lin (US 6,348,399).

In re claims1-3, 5-8 and 10, Lu et al., in related text (Col. 2, Lines 5-64) and figures (Figs. 1A-1F), disclose a method of forming electroplated solder on an organic circuit board for making flip chip joints and board to board solder joints, comprising: providing an organic circuit board 12 (Col. 3, Lines 30-39) including a surface bearing electrical circuitry that includes at least one contact pad 14; a solder mask layer 24 that is placed on board surface 12 and patterned to expose pad 14; a thin metal layer (UBM) 28/30 that is deposited over board surface 12; a resist layer 34 with at least one opening located at pad 14 that is deposited over thin metal layer (UBM) 28/30; a solder material 40 (Col. 8, Lines 52-58) that is formed in opening by electroplating (Col. 5, Lines 53-56); resist layer and thin metal layer beneath resist layer being removed (Figs. 1E-1F)

Lu et al., disclose all claimed subject matter, but fails to expressly disclose the method of forming UBM layer.

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Lin, in related text, (Col. 3, Lines 4-8 and 16-20) discloses a thin metal layer (UBM) is deposited by CVD, PVD or PECVD method. It would have been obvious to one with ordinary skill in the art at the time of the invention to modify the Lu et al., by the method as taught by Lin since it becomes possible that the manufacture of a model chip scale package can be relatively simplified and economical, yield highly reliable.

2. Claims 4 and 9 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lu et al., (US 6,358,836) in view of Lin (US 6,348,399) and further in view of Akram (US 5,903,058).

Lu et al., disclose all claimed subject matter, but fails to expressly disclose the thickness of the UBM layer.

Akram, in related text, (Col. 6, Lines 5-11) discloses the thickness of the UBM layer may be about 3000Å. However, given the substantial Lu et al., in view of Lin and in further view of Akram, it would have been obvious to one with ordinary skill in the art at the time of the invention to judiciously adjust and control the thickness of the UBM layer through routine experimentation and optimization to achieve optimum benefits (see MPEP 2144.05) and it would not yield any unexpected results.

3. Claims 11-14, 16-21 and 23 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lu et al., (US 6,358,836) in view of Lin (US 6,348,399) and further in view of Sheridan et al., (US 6,489,229).

In re claims11-14, 16-21 and 23, Lu et al., in related text (Col. 2, Lines 5-64) and figures (Figs. 1A-1F), disclose a method of forming electroplated solder on an organic circuit board for

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making flip chip joints and board to board solder joints, comprising: providing an organic circuit board 12 (Col. 3, Lines 30-39) including a surface bearing electrical circuitry that includes at least one contact pad 14; a solder mask layer 24 that is placed on board surface 12 and patterned to expose pad 14; a thin metal layer (UBM) 28/30 that is deposited over board surface 12; a resist layer 34 with at least one opening located at pad 14 that is deposited over thin metal layer (UBM) 28/30; a solder material 40 (Col. 8, Lines 52-58) that is formed in opening by electroplating (Col. 5, Lines 53-56); resist layer and thin metal layer beneath resist layer being removed (Figs. 1E-1F)

Lu et al., disclose all claimed subject matter, but fails to expressly disclose the method of forming UBM layer.

Lin, in related text, (Col. 3, Lines 4-8 and 16-20) discloses a thin metal layer (UBM) is deposited by electroless plating. It would have been obvious to one with ordinary skill in the art at the time of the invention to modify the Lu et al., by the method as taught by Lin since it becomes possible that the manufacture of a model chip scale package can be relatively simplified and economical, yield highly reliable.

Lu et al., disclose all claimed subject matter, but fails to expressly disclose the noble metal, such as gold, etc., should be avoided to be used as a part of the UBM layer.

Sheridan et al., in related text, (Col. 2, Lines 7-9) disclose a method for eliminating the Au layer formed on top of a Cu layer in a UBM stack. It would have been obvious to one with ordinary skill in the art at the time of the invention to modify the Lu et al., by the method as taught by Lin and Sheridan et al., since it becomes possible that the manufacture of a model

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chip scale package can be relatively simplified and economical. (See Sheridan et al., Col. 1, Lines 40-50).

4. Claims 15 and 22 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lu et al., (US 6,358,836) in view of Lin (US 6,348,399) and further in view of Sheridan et al., (US 6,489,229) and Akram (US 5,903,058).

Lu et al., disclose all claimed subject matter, but fails to expressly disclose the thickness of the UBM layer.

Akram, in related text, (Col. 6, Lines 5-11) discloses the thickness of the UBM layer may be about 3000Å. However, given the substantial Lu et al., in view of Lin and in further view of Akram, it would have been obvious to one with ordinary skill in the art at the time of the invention to judiciously adjust and control the thickness of the UBM layer through routine experimentation and optimization to achieve optimum benefits (see MPEP 2144.05) and it would not yield any unexpected results.

Conclusion

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to David Vu whose telephone number is (703) 305-0391 The examiner can normally be reached on Monday-Friday from 8:00am to 5:00pm. If attempt to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms., can be reached on (703)) 308-4910.

DV

David Vu.

HOAIHO